

Contents lists available at ScienceDirect

Journal of Solid State Chemistry



journal homepage: www.elsevier.com/locate/jssc

Ti₂GaC, Ti₄GaC₃ and Cr₂GaC—Synthesis, crystal growth and structure analysis of Ga-containing MAX-phases M_{n+1} GaC_n with M = Ti, Cr and n = 1, 3

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ARTICLE INFO

Article history: Received 11 November 2008 Received in revised form 27 December 2008 Accepted 3 January 2009 Available online 13 January 2009 *Keywords:* Single crystal growth Crystal structure Energy dispersive X-ray spectroscopy (EDXS) X-ray diffraction (XRD) Carbides

1. Introduction

Binary carbides and nitrides of group IV and V transition metals are important high temperature hard materials with extremely high melting points [1]. Recent investigations on ternaries such as Ti₃SiC₂ [2], Ti₃AlC₂ [3], Ti₄AlN₃ [4] and related compounds of the series $(MX)_n(MA)$ (M = "early" transition metal; A = main group metal; X = C, N; n = 1,2,3,... [5] ("MAX-phases") have shown excellent and unique material properties like damage and shock resistance or good thermal and electrical conductivity [6]. Among them compounds with the composition $M_2M'X$ (H-phase or 211-phase) are the most numerous by far. While M is usually a group 4 or 5 transition metal A shows high variability. It can be a main group metal (Al, Ga, In, Tl, Sn, Pb) or a meta-metal (Si, Ge, P, As) [6,7]. Most of the H-phases were already synthesised and characterised in the 1960s by Nowotny, Jeitschko, and coworkers [8,9].

According to their unique material properties [10] recent investigations focused on MAX-phases with A = Al and Si. Furthermore higher MAX-phases, i.e. 312- and 413-phases (n = 2, 3) are only known for A = Al, Si and Ge. Single crystal growth, especially of the higher MAX-phases, is difficult because

ABSTRACT

Single crystals of Ga-containing MAX-phases Ti₂GaC, Ti₄GaC₃, and Cr₂GaC were grown from a metallic melt generated by an excess of Ga. This technique allows the crystal growth at different temperatures to control the product distribution. Compounds developed were Ti₂GaC and TiC at 1500 °C, and Ti₂GaC and Ti₄GaC₃ at 1300 °C. Crystal structures were refined from single crystal data. Ti₂GaC and Cr₂GaC were previously known, and belong to the Cr₂AlC type as well as the solid solutions V₂Ga_{1-x}Al_xC and Cr₂Ga_{1-x}Al_xC. Ti₄GaC₃ is one of the few 413-phases (*P*6₃/*mmc*, *a* = 3.0690(4) Å, *c* = 23.440(5) Å) and the first Ga-containing representative. The crystal structures of MAX-phases are intergrowths of layers of an intermetallic *M*Ga in a hexagonal stacking sequence with carbidic layers (*M*C)_n of the NaCl type. The thickness of the layer depends from the value of *n*. The results of the structure refinements also demonstrate that also the structural details follow this description.

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of the high melting points. Therefore, studies of single crystals are very rare and most of the investigations deal with powder samples. Recently we have reported on synthesis and single crystal growth of the 413-phases Ta₄AlC₃ [11], and V₄AlC_{3-x} [12] using metal flux techniques. Furthermore we were able to prove the existence of solid solutions (Ti₄Al_{1-y}Sn_yN_{3-x}C_x [13]), carbon vacancies (V₄AlC_{3-x}, $x \approx 0.31$) [12]) and ordered super structures V₁₂Al₃C₈ [12]). In this article, we will report on the H-phases M_2 GaC (M = Ti, Cr), the solid solutions V₂Ga_{0.4}Al_{0.6}C and Cr₂Ga_{0.4}Al_{0.6}C, and Ti₄GaC₃, the first Ga-containing higher MAX-phase.

2. Experimental section

2.1. Syntheses, crystal growth, and characterisation

Single crystals of Ti₂GaC, Cr₂GaC, Ti₄GaC₃ and the solid solution V₂Ga_{1-x}Al_xC were synthesised from the elements with an excess of gallium. Cr₂Ga_{0.4}Al_{0.6}C was found as a by-product in the system Ga/Cr/C. As shown in Fig. 1, the distribution of products is significantly dependant on the temperature of the synthesis. Accordingly, the conditions were selected.

EDX (energy dispersive X-ray spectroscopy) and WDX (wavelength dispersive X-ray spectroscopy) measurements were performed on single crystals to ensure the correct composition. The ratio of *M*:Ga was determined by EDX with an accuracy of

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^{0022-4596/\$ -} see front matter \circledcirc 2009 Elsevier Inc. All rights reserved. doi:10.1016/j.jssc.2009.01.003



Fig. 1. Powder patterns from Ti/Ga/C; synthesis at: (a) 1680 °C, (b) 1600 °C, (c) 1500 °C, and (d) 1300 °C, calculated pattern for Ti₄GaC₃ (upper part in d)) is simulated from single crystal data.

 \pm 1 mol%. Furthermore WDX measurements were necessary to exclude the incorporation of light elements with *Z* between 4 and 13 because Ti frequently contains small amounts of nitrogen caused by the high stability of TiN. Especially nitrogen is able to substitute carbon in binary and ternary *M* carbides [1] and cannot be reliably determined from X-ray data. WDX will detect nitrogen in amounts exceeding 3 mol%. Accuracy for the WDX was poorer comparable to the EDX in the simultaneous determination of *C* and other metals due likely to scaling problems [14,15].

XRD patterns were recorded with a Siemens D5000 (CuK α 1 radiation, Ge-monochromator, gas-filled PSD, Debye–Scherrer

geometry, transmission). Single crystal investigations were done at room temperature using graphite monochromated MoK α radiation. A numerical absorption correction was applied using equivalent method (Programme XSHAPE/XRED [18]). Structure models for the refinements (programme SHELXTL [19]) were taken from the literature.

SEM pictures and EDX measurements were performed using a Jeol SM 6400 (Ge detector). For WDX investigations, we employed the Cameca SX 50 (analyzer crystal PC2, diamond and c-BN as standards).

Ti₂GaC: Single crystals of Ti₂GaC were obtained from the elements by the following procedure. Commercially available powders (Ti, Ventron, 99.5%; C, graphite, Chempur, 99.9+%), or small pieces (Ga, Alfa Aesar, 99.99%) were mixed in a ratio of 5:2:7 and pressed into a pellet (total mass: ca. 300 mg). The pellet was put into a corundum crucible and guickly (200 K/h) heated to 1500 °C under an argon atmosphere. The sample was held for 50 h at 1500 °C, cooled to 900 °C with a cooling rate of 5 K/h, held for 30 h and then cooled at 30 K/h to 600 °C and with 100 K/h to RT. The excess metal of the solidified melt was removed by dissolving the regulus in half-concentrated aqueous HCl. The residue was washed and dried. Small hexagonal platelets were identified as Ti₂GaC. The XRD pattern was indexed with a hexagonal unit cell with a = 3.0663(4) Å and c = 13.312(2) Å (Fig. 1c). Additional lines were assigned to TiC or Ti₄GaC₃. EDX measurements on selected single crystals revealed a ratio Ti:Ga of 69:31. WDX investigations confirmed the presence of the elements Ti, Ga and C and the absence of N and O.

Ti₄GaC₃: Single crystals of Ti₄GaC₃ were obtained from the elements similar to Ti₂GaC, but at lower temperatures. Ti, C, and Ga were mixed at a ratio of 5:2:10 (total mass 300 mg) and pressed to a pellet. The temperature program was the same as for Ti₂GaC, but 1300 °C as the maximum temperature. After dissolution the residue contained hexagonal platelets (Ti₂GaC) and columns (Ti₄GaC₃, Fig. 2). The powder pattern showed the lines of Ti₂GaC and Ti₄GaC₃ (Fig. 1d). The refinement of the indexed reflections resulted in a hexagonal unit cell with a = 3.0582(8)Å and c = 23.370(4)Å. EDX measurements on selected single crystals revealed a ratio of 80:20 for Ti:Ga and the absence of other elements With Z > 13. WDX investigations confirmed the presence of the elements Ti, Ga, and C, an atomic ratio of 47:11:42 and the absence of N and O.

Cr₂GaC: Single crystals of Cr₂GaC were obtained from the elements. Commercially available powders (Cr, Alfa Aesar, 99.5%; C, graphite, Chempur, 99.9+%) or small pieces (Ga, Alfa Aesar,



Fig. 2. SEM picture of a Ti₄GaC₃ single crystal.

99.99%) were mixed at a ratio of 5:2:11, pressed into a pellet (total mass: ca. 300 mg) and submitted to the same procedure as described for the Ti compounds ($T_{max} = 1300 \,^{\circ}$ C). Small hexagonal platelets were characterised as Cr₂GaC. The XRD pattern was indexed with a hexagonal unit cell with a = 2.8929(8)Å and c = 12.648(4)Å. EDX measurements on selected single crystals revealed a ratio Cr:Ga of 66:34.

V₂Ga_{1-x}Al_xC: Small single crystals were obtained from the elements. Commercially available powders (V, ChemPur, 99.5+%; Al, 99.9%, Ventron; C, Carbon Black, Strem Chemicals, 99.9+%) or small pieces (Ga, Alfa Aesar, 99.99%) were mixed at ratios of 6:10:1:5 and 6:7.5:1:7.5, pressed into a pellet (total mass: ca. 300 mg) and submitted to the same procedure like the Ti-compounds ($T_{max} = 1500$ °C). Very small hexagonal platelets were characterised as 211-phases. Small amounts of V₆C₅ [7] were found as a by-product. The XRD pattern of the Al-rich sample was indexed with a hexagonal unit cell with a = 2.921(1)Å and c = 13.047(9)Å. The values for the sample with equal amounts of Al and Ga were a = 2.928(1)Å and c = 12.998(5)Å. EDX measurements on selected single crystals revealed a ratio Cr:Ga:Al of 65:16:19 and 66:20:14, respectively.

Cr₂Ga_{1-x}Al_xC (*x*≈0.60): A few small black hexagonal platelets were obtained, with single crystals of Cr₇C₃ [16] as a by-product, from the reaction of Cr, Ga, and C (molar ratio 5:7:2) at 1680 °C in a corundum crucible. X-ray investigations revealed a 211-MAX-phase. The XRD pattern was indexed with a hexagonal unit cell with *a* = 2.8668(13) Å and *c* = 12.762(6) Å. In agreement with the EDX results the refinement of the single crystal data resulted in a mixed crystal Cr₂Ga_{1-x}Al_x with *x*≈0.60). This composition was confirmed for several crystals of this batch. The unexpected Al content may be explained by the high reaction temperature in combination with the Al₂O₃ crucible.

2.2. Structure solution and refinement

Ti₂GaC: A black hexagonal platelet was isolated from the Ga-melt and investigated using a single crystal diffractometer equipped with an image plate detector (STOE, IPDS I, MoK α radiation). All reflections were indexed with a hexagonal unit cell with lattice parameters of a = 3.0764(4)Å and c = 13.378(3)Å. Unit cell dimensions and reflection conditions (*hhl* with l = 2n) were characteristic for a H-phase. The refinement was started with the parameters of a Cr₂AlC type [8] in space group *P*6₃/*mmc* and performed quick convergence. Finally *R*-factors of $R_1(F) = 0.0267$ and $wR_2(F^2) = 0.0628$ were obtained with 103 unique reflections (61 with $I > 2\sigma(I)$) and 10 parameters. Details are listed in Tables 1–3.

Ti₄GaC₃: A hexagonal column was isolated from the Ga melt which had been heated to1300 °C. According to unit cell dimensions (a = 3.0690(4) Å, c = 23.440(5) Å), symmetry (Laue-class 6/mmn), and reflection conditions (*hhl* with l = 2n) the refinement was started in space group $P6_3/mmc$ with the structure model of a 413-phase [11-13]. At the final stage of the refinement, it was discovered that the displacement parameter of Ga on site 2c was much too large (factor of 3) compared to Ti₂GaC. Furthermore an additional site (2d) occurred with a residual density of $5.7 e^{-}/Å^{3}$. According to the crystal structure and the results of the elemental analysis (see below) two partially occupied positions for Ga were introduced. A refinement with free occupation factors yielded values of 81.6(13)% for site 2c and of 8.9(8)% for site 2d ($R_1(F) = 0.040$, w $R_2(F^2) = 0.103$). The assumption of a complete occupation of the Ga-layer (sof's of 2d and 2c sum up to 1/12) resulted in occupations of 86.1(14)% and 13.9(14)%. Because defects on the A-site are not described for MAX-phases and in agreement with the EDX results we utilised

Table 1

Structure refinement of Ti₂GaC, Ti₄GaC₃, Cr₂GaC, V₂Ga_{1-x}Al_xC (x = 0.56, 0.43), and Cr₂Ga_{0.40}Al_{0.60}C.

	Ti ₂ GaC	Ti ₄ GaC ₃	Cr ₂ GaC	Cr ₂ Ga _{0.4} Al _{0.6} C	$V_2Ga_{0.44}Al_{0.56}C$	$V_2Ga_{0.57}Al_{0.43}C$
Crystal shape	Hexagonal platelet	Hexagonal prism	Hexagonal platelet	Hexagonal platelet	Hexagonal platelet	Hexagonal platelet
Crystal colour	Metallic lustrous	Metallic lustrous				
Crystal size (mm ³)	$0.1\times0.1\times0.01$	$0.025 \times 0.025 \times 0.1$	$0.05 \times 0.05 \times 0.001$	$0.04 \times 0.04 \times 0.001$	$0.02\times0.02\times0.001$	$0.02 \times 0.02 \times 0.001$
Formula weight (g/mol)	177.49	297.27	185.73	160.08	159.74	160.08
Crystal system	Hexagonal	Hexagonal	Hexagonal	Hexagonal	Hexagonal	Hexagonal
Space group	P6 ₃ /mmc	P6 ₃ /mmc				
Lattice constants	a = 3.0764 (4)Å,	$a = 3.0690 (4) \text{\AA},$	$a = 2.9008 (4) \text{\AA},$	a = 2.875 (2)Å,	$a = 2.9199 (17) \text{\AA},$	a = 2.9252 (13)Å,
	$C = 13.378 (3) \text{\AA}$	b = 23.440(5)Å	c = 12.632 (3)Å	$c = 12.679 (11) \text{\AA}$	$c = 13.029 (8) \text{\AA}$	$c = 12.959 (9) \text{\AA}$
Cell volume (Å ³)	109.65	191.20	92.05	90.77	96.20	96.03
Formula units	2	2	2	2	2	2
Density, calculated (g/cm ³)	5.38	5.17	6.70	5.86	5.52	5.71
Radiation	ΜοΚα	ΜοΚα	ΜοΚα	ΜοΚα	ΜοΚα	ΜοΚα
θ -range	$-4 \leqslant h \leqslant 4$, $-4 \leqslant k \leqslant 4$,	$-4 \le h \le 4, -4 \le k \le 4,$	$-4 \leqslant h \leqslant 4$, $-4 \leqslant k \leqslant 4$,	$-4 \le h \le 4, -4 \le k \le 4,$	$-4 \leqslant h \leqslant 4, -4 \leqslant k \leqslant 4,$	$-4 \le h \le 4, -4 \le k \le 4,$
-	$-20 \leq l \leq 20$	-30 <i>≤l≤</i> 30	$-18 \leq l \leq 18$	$-19 \le l \le 19$	–22≤l≤22	<i>-</i> 22 <i>≤l≤</i> 22
$2\theta_{\max}$ (Deg)	65	65	65	65	75	75
Diffractometer	STOE IPDS I	STOE IPDS I	STOE IPDS I	STOE IPDS I	STOE IPDS II	STOE IPDS II
Data collection	$0^{\circ} \leq \omega \leq 200^{\circ}; \ \varphi = 0^{\circ},$	$0^{\circ} \leq \omega \leq 200^{\circ}; \ \varphi = 0^{\circ},$	$0^{\circ} \leq \omega \leq 200^{\circ}; \ \varphi = 0^{\circ},$	$0^{\circ} \leq \omega \leq 200^{\circ}; \ \varphi = 0^{\circ},$	$0^{\circ} \leqslant \omega \leqslant 200^{\circ}; \ \varphi = 0^{\circ},$	$0^{\circ} \leqslant \omega \leqslant 200^{\circ}; \ \varphi = 0^{\circ},$
	$\Delta \omega = 2^{\circ}$	$\Delta \omega = 2^{\circ}$				
Measure time (s)	180	120	360	120	600	600
Reflections measured	1574	1265	1153	1312	637	987
Independent reflections	103	103	90	88	117	113
Reflections $I > 2\sigma(I)$	61	84	63	58	75	77
Max/min transmission	0.1321; 0.0886	0.1644; 0.0936	0.1321; 0.0886	0.1109; 0.0257	0.6418; 0.3217	0.5709; 0.2884
R _{int} , R _{sigma}	0.1105, 0.0463	0.1242, 0.0590	0.1380, 0.0338	0.1293, 0.0450	0.0611, 0.0231	0.0924, 0.0189
Absorption coefficient (mm ⁻¹)	18.85	14.72	25.58	17.51	15.50	17.19
Extinction coefficient [19]	0.025 (9)	0.030 (14)	0.294 (19)	0.015 (15)	0.337 (42)	0.298 (29)
Residual electron e ⁻ /Å ³ min, max, sigma	+0.94, -0.87, 0.23	+1.87, -3.53, 0.31	+0.48, -0.56, 0.16	+0.61, -0.74, 0.19	+0.75, -1.32, 0.22	+0.46, -0.68, 0.13
Weighting function [19]	0.0338; 0.0	0.0592; 2.71	0.028; 0.0	0.0262; 0.03	0.0421; 0.0	0.0247; 0.0
Number of parameters	9	14	9	9	10	10
R-factors	$R_1(F) = 0.0267;$ w $R_2(F^2) = 0.0628$	$R_1(F) = 0.0516;$ w $R_2(F^2) = 0.125$	$R_1(F) = 0.0174;$ w $R_2(F^2) = 0.0461$	$R_1(F) = 0.0326;$ w $R_2(F^2) = 0.0848$	$R_1(F) = 0.0278;$ w $R_2(F^2) = 0.0636$	$R_1(F) = 0.0158;$ w $R_2(F^2) = 0.0357$

Table 2

Coordinates, displacement parameters (in 10^4 Å^2), and site occupation factors^a.

Compound atom	Site	x	у	Z	$U_{\rm eq}$	sof ^b	<i>U</i> ₁₁	U ₃₃
Ti ₂ GaC Ti Ga C	4f 2d 2a	1/3 2/3 0	2/3 1/3 0	0.08653 (13) 1/4 0	160 (4) 128 (6) 74 (28)	1.01 (1) 0.98 (1) 1.04 (5)	57 (5) 138 (7) 60 (36)	69 (8) 108 (9) 102 (45)
Ti₄GaC₃ Ti1 Ti2 Ga Ga' C1 C2	4e 4f 2c 2d 4f 2a	0 1/3 1/3 2/3 2/3 0	0 2/3 2/3 1/3 1/3 0	0.15637 (10) 0.05582 (11) 1/4 1/4 0.1065 (6) 0	117 (8) 124 (8) 141 (10) ^c 141 (10) ^c 178 (30) ^d 13 (27) ^d	$\begin{array}{c} 1.00 \ (2) \\ 1.00 \ (2) \\ 0.86 \ (1)^c \\ 0.14 \ (1)^c \\ 1.02 \ (7) \\ 1.42 \ (10) \end{array}$	86 (11) 83 (11) 283 (19) ^c 283 (19) ^c	179 (14) 205 (14) 218 (19) ⁶ 218 (19) ⁶
Cr ₂ GaC Cr Ga C	4f 2d 2a	1/3 2/3 0	2/3 1/3 0	0.08527 (5) 1/4 0	95 (3) 123 (4) 111 (12)	1.00 (1) 1.00 (1) 1.05 (4)	88 (4) 129 (4) 95 (17)	110 (4) 112 (5) 145 (27)
V ₂ Ga _{0.44} Al _{0.56} C V Al/Ga ^c C	4f 2d 2a	1/3 2/3 0	2/3 1/3 0	0.08579 (5) 1/4 0	50 (3) 82 (5) 59 (9)	1.00 (1) 0.559/0.441 (7) ^c 1.09 (4)	48 (4) 94 (6) 44 (14)	54 (4) 59 (5) 87 (16)
V ₂ Ga _{0.57} Al _{0.43} C V Al/Ga ^c C	4f 2d 2a	1/3 2/3 0	2/3 1/3 0	0.08587 (3) 1/4 0	58 (2) 86 (3) 67 (6)	1.00 (1) 0.434/0.566 (4) ^c 0.99 (3)	58 (2) 99 (3) 65 (9)	57 (3) 59 (3) 71 (10)
Cr ₂ Ga _{0.40} Al _{0.60} C Cr Al/Ga ^c C	4f 2d 2a	1/3 2/3 0	2/3 1/3 0	0.08512 (7) 1/4 0	139 (5) 168 (8) 184 (18)	1.00 (1) 0.599/0.401 (4) ^c 1.03 (3)	128 (6) 165 (9) -	162 (7) 173 (10) -

^a esd's in parentheses, $U_{11} = U_{22} = 2 U_{12}, U_{23} = U_{13} = 0$.

^b In order to check for mixed occupations and/or vacancies site occupation factors were treated by turns as free variables at the end of the refinement.

^c Coupled refinement (see text).

^d U_{iso}.

the idealised composition Ti_4GaC_3 for the discussion. In contrast to the refinement of Ti₂GaC, Cr₂GaC and several other MAX-phases like Ta₄AlC₃ [11], Ta₃AlC₂ [11] and V₂AlC [12] the displacement parameter of carbon on the special site 2a is very small and the site occupation factor is significantly enlarged. Because nitrogen and oxygen were not detected for this single crystal it is probably caused by the disorder of Ga and other defects like stacking faults which can influence the electron density at the origin and other very special sites. Therefore the carbon atoms were refined with isotropic displacement parameters. Finally R-factors of $R_1(F) = 0.0516$ and $wR_2(F^2) = 0.125$ were obtained. Details are listed in Tables 1–3.

The disorder of Ga was observed for several crystals. The amount of Ga on site 2*b* was between 14% and 16%. The data given above represent the results for the best refinement and were obtained from the single crystal used for the EDX and WDX measurements.

Cr₂GaC: A black hexagonal platelet was isolated from the Ga melt. All reflections were indexed with a hexagonal unit cell with lattice parameters of a = 2.9008(4)Å and c = 12.632(3)Å. The refinement was started with the parameters of a Cr_2AlC type [8] and performed quick convergence. Finally R-factors of $R_1(F) = 0.0174$ and $wR_2(F^2) = 0.0461$ were obtained with 90 unique reflections (63 with $I > 2\sigma(I)$) and nine parameters. Details are listed in Tables 1-3.

V₂Ga_{1-x}Al_xC ($x \approx 0.43$ and 0.56): A black hexagonal platelet was isolated from the Ga/Al-melt. All reflections were indexed with a hexagonal unit cell. The lattice parameters were in good agreement with the powder data. For $V_2Ga_{0.57}Al_{0.43}C$ the values were a = 2.925(1)Å and c = 12.959(9)Å, for V₂Ga_{0.44}Al_{0.56}C a = 2.920(1)Å and c = 13.029(8)Å. The refinement was started with the parameters of a Cr₂AlC-type [8] and performed quick convergence. The mixed occupation of site 2d by Ga and Al was obvious from difference Fourier syntheses. The ratio Ga:Al was refined as a free parameter. For V₂Ga_{0.57}Al_{0.43}C the final *R*-factors were $R_1(F) = 0.0158$ and $wR_2(F^2) = 0.0357$ (113 unique reflections, 77 with $I > 2\sigma(I)$ and for $V_2Ga_{0.44}Al_{0.56}C$ $R_1(F) = 0.0278$ and $wR_2(F^2) = 0.0636$ (117 unique reflections, 75 with $I > 2\sigma(I)$). Details are listed in Tables 1-3.

 $Cr_2Ga_{1-x}Al_xC$ ($x \approx 0.60$): A small fragment of a black hexagonal platelet was used for the structure analysis. All reflections were indexed with a hexagonal unit cell with lattice parameters of a = 2.8752(17)Å and c = 13.679(9)Å. According to the experimental conditions the refinement was started with the parameters of Cr₂GaC. Surprisingly the refinement presented different results. The site 2a which is usually occupied by C seemed to be empty, while the difference Fourier synthesis showed a residual electron density of $6.7 e^{-1}/Å^{3}$ at a site 4e with z = 0.1552, i.e. the octahedral voids between the Cr- and Ga-layers. The occupation of this site by carbon led to an occupation of 50%, R-values of $R_1 = 0.062$ and $wR_2(F^2) = 0.137$ and the expected/assumed composition Cr₂GaC. The refinement with a free occupation factor for Ga improved the *R*-values (0.051 and 0.112, respectively; sof(Ga) = 84%) but did not change the structure model, i.e. the site

Table 3 Selected distances (in (Å)) and angles (in (deg)), esd's in parentheses.

Ti ₂ GaC Ti-C Ti-Ga Ti-Ti Ti-Ti	2.120 (1) 3x 2.8174 (14) 3x 2.918 (3) 3x 3.0764 (4) 6x	Ga-Ga Ga-Ti C-Ti Ti-C-Ti	3.0764 (4) 6x 2.8174 (14) 6x 2.120 (1) 6x 86.97 (6)/93.03 (6)
<i>Ti₄GaC</i> ₃ Ti1-C1 Ti1-Ga Ti1-Ti2 Ti1-Ti1	2.123 (8) 3x 2.821 (1) 3x 2.949 (3) 3x 3.0690 (4) 6x	Ti2-C1 Ti2-C2 Ti2-Ti1 Ti2-Ti2 Ti2-Ti2	2.133 (8) 3x 2.203 (2) 3x 2.949 (3) 3x 3.0690 (4) 6x 3.160 (3) 3x
Ga-Ti1 Ga-Ga C1-Ti1 C1-Ti2 C2-Ti2	2.821 (1) 6x 3.0690 (4) 6x 2.123 (8) 3x 2.133 (8) 3x 2.203 (2) 6x	Ti2-C1-Ti2 Ti1-C1-Ti1 Ti1-C1-Ti2 Ti2-C2-Ti2 Ti2-C2-Ti2	87.7 (1) 92.6 (5) 92.0 (5)/179.6 (1) 88.3 (1) 91.7 (1)
Cr ₂ GaC Cr-C Cr-Ga Cr-Cr Cr-Cr	1.9913 (4) 3 <i>x</i> 2.6710 (6) 3 <i>x</i> 2.729 (1) 3 <i>x</i> 2.9008 (4) 6 <i>x</i>	Ga-Ga Ga-Cr C-Cr Cr-C-Cr	2.9008 (4) 6x 2.6710 (6) 6x 1.9913 (4) 6x 86.50 (2)/93.50 (2)
V ₂ Ga _{0.44} Al _{0.56} C V-C V-Al/Ga V-V V-V V-V	2.023 (1) 3x 2.724 (1) 3x 2.800 (2) 3x 2.920 (2) 6x	Al/Ga-Al/Ga Al/Ga-V C-V V-C-V	2.920 (2) 6x 2.724 (1) 6x 2.023 (1) 6x 87.59 (4)/92.41 (4)
V ₂ Ga _{0.57} Al _{0.43} C V-C V-Al/Ga V-V V-V	2.0225 (8) 3x 2.716 (1) 3x 2.794 (2) 3x 2.925 (1) 6x	Al/Ga-Al/Ga Al/Ga-V C-V V-C-V	2.925 (1) 6x 2.716 (1) 6x 2.0225 (8) 6x 87.37 (3)/92.63 (3)
Cr ₂ Al _{0.60} Ga _{0.40} C Cr-C V-Al/Ga V-Cr V-Cr	1.980 (1) 3x 2.669 (2) 3x 2.729 (1) 3x 2.875 (2) 6x	Al/Ga-Al/Ga Al/Ga-Cr C-Cr Cr-C-Cr	2.875 (2) 6 <i>x</i> 2.667 (2) 6 <i>x</i> 1.980 (1) 6 <i>x</i> 86.88(2)/93.12(2)

2*a* remained empty and the site 4*f* half occupied. All in all the results seemed to be plausible. But the usual check of the composition by EDX had shown that these crystals contain considerable amounts of aluminium with a molar ratio for Cr:Al:Ga of 66:20:14. Therefore the structure model was modified when taking into account a mixed Ga/Al occupation of site 2*d*. Now the 2*a* site is fully occupied by carbon and the 4*e* site is empty. Furthermore the *R*-factors were significantly lower and the displacement parameters similar to those of Cr₂GaC. The ratio Al:Ga was found to be 59.9:40.1(4)% in excellent agreement with the EDX measurements. Finally *R*-factors of $R_1(F) = 0.032$ and $wR_2(F^2) = 0.086$ were obtained with 88 unique reflections (58 with $I > 2\sigma(I)$) and nine parameters. Details are listed in Tables 1–3. A note, the observations described above were made for several crystals.

Further details on the structure refinements (complete list of distances and angles, F_0/F_c -list) may be obtained from: Fachinformationszentrum Karlsruhe, D-76344 Eggenstein-Leopoldshafen (Germany) (fax: +49724808666; e-mail: crysdata@fiz-karlsruhe. de) on quoting the registry numbers CSD—419117 (Ti₂GaC), 419118 (Ti₄GaC₃), 419116 (Cr₂GaC), 419245 (V₂Ga_{0.44}Al_{0.56}C), 419246 (Cr₂Ga_{0.57}Al_{0.43}C), and 419119 (Cr₂Ga_{0.4}Al_{0.6}C).

3. Results and discussion

The investigations of the system Ti/Ga/C indicate that temperature plays a key role in the syntheses using the auxiliary metal technique. Fig. 1 shows the powder diagrams recorded from samples obtained at different temperatures. At 1680 °C only the reflections of TiC were observed. At 1600 °C the main product remains as TiC but the reflection profiles show a broadening probably caused by the formation of non-stoichiometrical TiC_{1-x}. At 1500 °C, it is clear a ternary carbide forms. The diagram shows a mixture of Ti₂GaC and TiC. At 1300 °C, the main products are Ti₄GaC₃ and Ti₂GaC while TiC is not observed.

The results confirm the general tendency that at higher temperatures the formation of simple compounds (binary carbide) is favoured. At lower temperatures the more complex ternary carbides Ti₂GaC and/or Ti₄GaC₃ are formed. Similar observations were made for other ternary carbides synthesised by the auxiliary metal technique [20,21].

Ti₂GaC: The crystal structure of Ti₂GaC (Fig. 3) belongs to the Cr₂AlC type, a so-called 211- or H-phase, confirming the results of Jeitschko et al. [9e] (a = 3.064 Å, c = 13.305 Å). The metal atoms form a hexagonal closest packing (hcp) with Ga in every third layer. The C atoms occupy all octahedral voids between the layers of Ti atoms. Because the 211-phase bases on a hcp, both metals have an anticuboctahedral coordination. For Ga it is built up by six Ga and six Ti atoms, for Ti three Ga and nine Ti atoms with three additional C atoms.

Distances are determined by the lattice constants and the free site parameter z_{Ti} . With a value of 0.0865 it is quite close to that originally found for Cr₂AlC by Jeitschko et al. [8] and recently confirmed for V₂AlC [12]. The small deviation from the ideal value for a hcp ($z_{\text{Ti}} = 1/12 \approx 0.0833$) can be explained by the influence of the occupation of the octahedral site by carbon. The Ti–C distances of 2.120Å are slightly shorter than in the binary TiC (2.164Å) and the CTi₆ octahedra are compressed along [001]



(Ti–C–Ti: 93.0°). This is a well-known phenomenon in 211-phases. The shortest metal–metal distances are between Ga and Ti layers (2.817 Å), and the longest within the layers (3.076 Å, i.e. lattice parameter a).

Ti₄GaC₃: Ti₄GaC₃ represents the forth example for a 413-phase. Its crystal structure (Fig. 4) consists of a closest packing of metal atoms with a layer sequence *bAcBABcAbCaBCBaCb* and carbon atoms in octahedral voids (Ga layers in bold letters, C in octahedral voids and italics). The coordination polyhedra of the atoms (Fig. 5) can be derived directly from this building principle, i.e. an anticuboctahedron (six Ga and six Ti atoms) for gallium, a cuboctahedron (12 Ti-atoms) plus six C-atoms for Ti2, an anticuboctahedron (nine Ti and three Ga atoms) plus three C atoms for Ti1 and Ti₆ octahedra for both of the C atoms.

According to the intergrowth concept the carbide part is enlarged compared to Ti_2GaC and now contains three layers of the NaCl type. There are two different C-atoms with C2 in the "central" layer and C1 in the "outer" layer. These differences are also mirrored in the Ti–C distances. The "central" distance C2–Ti2 amounts to 2.203 Å and is slightly longer than in binary TiC. The "outer" distance C1–Ti1 is significantly shorter (2.120 Å) with C1–Ti2 in between (2.133 Å). Similar observations were made for Ta₄AlC₃ (2.230/2.206/2.166 Å; TaC: 2.228 Å). To emphasise, for Ti₂GaC the CTi₆ octahedra are compressed along [001]. According to the position of Ti₄GaC₃ between Ti₂GaC and TiC this compression is also present in the "outer"octahedron (Ti1–C1–Ti1: 92.8°; Ti2–C1–Ti2: 91.7°). In contrast the "central" octahedron is slightly elongated (Ti2–C2–Ti2: 88.3°) and accordingly the Ti2–Ti2 distances between the central layers are longer (3.160 Å) than in TiC (3.06 Å) while the outer distances Ti1–Ti2 are shorter (2.949 Å).

The intermediate position of Ti_4GaC_3 between TiC and Ti_2GaC is also valid for the valence sums calculated according to Brown [22]. Although the concept of valence sums is more adequate for ionic and covalent compounds, it is also applicable for intermetallics to get qualitative statements. For TiC the values are 7.10 for Ti and 4.16 for C. In Ti_2GaC the valence sums are significantly lower for Ti (5.79, 2.34 from Ti–C bonds) because there are only three Ti–C bonds, and higher for C (4.69). Ga has a value of 2.61. In Ti_4GaC_3 the values for Ti2 (7.12, 4.14 from Ti–C bonds) and C2 (3.74) are very close to TiC while those for Ti1 (5.70, 2.32 from Ti–C bonds), C1 (4.59) and Ga (2.61) are similar to Ti_2GaC . Therefore, an estimation of bond distances and atomic coordinates for MAX-phases based on valence sums and the general building principle described in [11] is possible [23].



Fig. 4. Crystal structure of Ti₄GaC₃.



Fig. 5. Coordination polyhedra of Ti in Ti₄GaC₃.

The occupation of site 2b (instead of site 2c) by Ga changes the stacking sequence from (hhhcc)₂ to (hcccc)₂. The coordination of the 2b-site is still an anticuboctahedron but the surrounding of Ti1 is changed to a cuboctahedron. The splitting of the Ga-site was not limited to a singular crystal but was also confirmed for several other crystals from different batches. Values between 12% and 14% were found for the occupation of site 2b. A similar disorder of the metal layer was also observed for the MAX-phase Ti₃AlC₂ [20,23]. Two polymorphs are described for Ti₃SiC₂ [24]. The difference between both is the position of Si on one of these two sites. For Ti₃GeC₂ there is a pressure-induced phase transition at 27 GPa between these two polymorphs [25].

Very recently Lin et al. reported on a second modification of Ta_4AlC_3 [26]. On the basis of TEM/STEM investigations and electron diffraction (SAED, CBED) they described a structure where all metal atoms were in a hexagonal closest packing. This would imply that the CTa_6 -octahedra share common faces along [001]. Although many binary and ternary transition metal carbides with CTM_6 octahedra are known [1,7] there is no example with this structural feature. One explanation would be the formation of vacancies as proven for $V_{12}Al_3C_8$ [12], but also in this case there are only cubic sequences within the carbide layers.

Cr₂GaC: Cr₂GaC also belongs to the Cr₂AlC-type, and confirms the earlier report of Jeitschko et al. [9a]. Based on powder data, they assigned it to an H-phase with lattice constants of a = 2.886Å and c = 12.616 Å. The differences between Cr₂GaC and Ti₂GaC are very small. Because of the smaller metal radius of Cr (Cr: 1.28 Å, Ti: 1.45 Å) lattice constants and distances are slightly reduced. The free site parameter z_{Cr} is nearly the same (0.0853). The Cr–C-distances of 1.991 Å are slightly shorter than in the metastable binary CrC (2.02 Å) [27]. The CCr₆-octahedra are compressed in the crystallographic z-direction leading to a Cr–C-Cr angle of 93.5° and Cr–Cr distances of 2.729 Å between the Cr-layers. The shortest metal–metal distances are between Ga- and Cr-layers (2.671 Å), the longest ones within the layers (2.901 Å).

 $V_2Ga_{1-x}Al_xC$ and $Cr_2Ga_{1-x}Al_xC$: The values of the lattice parameters obtained both from powders and single crystals are consistent with the formation of an ideal solid solution and follow Vegard's law. A special feature of these solid solutions is that the electron density on the Ga/Al site is very similar to vanadium and chromium, respectively. As a consequence all strong reflections can be indexed by a subcell with c' = 1/3c compatible with a simple hexagonal closest packing. The super cell is only defined by the carbon atoms. In the powder patterns the strongest super cell reflections 002 and 104 have only 1% intensity of the strongest reflection 103. Therefore reliable statements on the localisation of the carbon atoms require the investigation of single crystals.

The example of $V_2Ga_{1-x}Al_xC$ shows that even the *z*-parameter of V follows Vegard's law. For $V_2AlC z_V$ is 0.08558 [12]. Because this is the only free site parameter of a 211-phase lattice parameters and all distances of solid solutions can be derived from the corresponding ternary compounds.

The results on the refinement of the solid solutions were included to this publication for several reasons. First it proofs the existence of the solid solutions $V_2Ga_{1-x}Al_xC$ and $Cr_2Ga_{1-x}Al_xC$. The ratio of the metals can reliably be determined on the basis of single crystal X-ray data in these cases. Solid solutions are very common in MAX-phases and can occur for different positions, i.e. $Ti_{2-x}V_xAlC$ [28], $Ti_3Al_{1-x}Si_xC_2$ [23], $Ti_2Sn_{1-x}Al_xC$ [29], $Ti_3Sn_{1-x}Al_xC_2$ [23], $Ti_2AlC_{1-x}N_x$ [30], $Ti_4Al_{1-x}Sn_xN_{1-y}C_y$ [13]. These solid solutions are of practical importance because they strongly influence the material properties [30]. Second it is an example for the easy occurrence of unexpected contaminations, especially in those cases where the sample is not completely characterised, i.e. single crystals by X-ray investigations or electron microscopy. Third we

have learned that the refinement may converge to a local minimum with a plausible structure which may not be the right solution. This may be caused by the high (pseudo)symmetry of MAX-phases and the great difference of the electron numbers (i.e. Ta/Sn and C/N), in combination with stacking faults and different types of solid solutions. An example for possible problems is the confusion on the structure of Ti₄AlN₃ [31].

4. Conclusions

The use of molten metals as a solvent enables the synthesis of new MAX-phases and the growth of single crystals. The access to reliable structural data on the basis of single crystals allows a more detailed discussion of geometrical relations in 413-phases. Usually atomic parameters are derived from a comparison of calculated and observed intensities. While an estimation of the metal parameters is obtainable from powder intensity data the reliable determination of the carbon sites is only possible from single crystal and/or neutron diffraction measurements [32].

The building principle of MAX-phases $(MC)_nMA$ is quite simple. They are intermediates between an alloy MA with hexagonal closest packing and the binary carbide MC with NaCl structure, where n determines the cut-out of the carbide part. In general the structural details follow this connection. For higher numbers of nthe M-C distances approach those of the binary carbide while the most significant deviations are observed for the carbide layer closest to the layer of A.

Despite the close relations between the different MAX-phases there are some systematic differences. For the Al-containing MAXphases the lattice parameter *a* is slightly larger for the 413-phases $(Ti_4AlN_3 [4], Ta_4AlC_3 [11] and V_4AlC_{3-x} (or V_{12}Al_3C_8, respectively)$ [12]) than for the corresponding 211-phases. The same is true for the 312-phases Ta₃AlC₂ [11] and Ti₃AlC₂ [20,33]. The opposite behaviour is observed for Ti_4GaC_3 and Ti_2GaC . With A = Ge, the only example where two different MAX-phases are described, the *a* lattice parameters are virtually identical (Ti₃GeC₂: a = 3.077 Å [34], Ti₂GeC: a = 3.079 Å [9b]). Obviously the atomic radius of the metal A has a subtle influence on the M-C interaction which is planned to be investigated by band structure calculations [35]. This more complex behaviour is found for the 211-phases, too. Although the atomic radius of Ga is smaller than for Al, the lattice parameter *a* of the Ga-containing H-phases is larger than for the corresponding Al-phases (see Table 4). But in total the unit cell volume of the Ga-phases is smaller. A more detailed discussion of the geometrical aspects of 211-phases will follow based on future single crystal data for single crystals obtained through the auxiliary metal technique. This is in line with our previous results on the synthetic potential of metallic melts [36], which enables the formation of new high-melting compounds at lower temperatures and/or the growth of single crystals [37].

For the 413-phase Ti₄GaC₃, it was demonstrated that a disorder of Ga occurs systematically. Similar stacking variants/faults were already reported for other MAX-phases, mainly on the basis of (HR)TEM investigations [38].

The mechanical properties of MAX-phases are intensely investigated (for example [2,5]). According to the lack of single crystals of sufficient size hardness measurements are done on sintered samples. Additionally the compressibility was measured [39] in order to estimate the hardness. The only exception seems to be Ti₃SiC₂ [40] where single crystals are grown via a CVDprocess. The access to well-shaped single crystals (Fig. 2) via metallic melts enables (micro)hardness measurements of further MAX-phases. The corresponding measurements are in progress [41].

Table 4

Lattice parameters (in (Å)) and metal radii (in (Å), according to [43]) of H-phases M_2AC (M = Ti, V, Cr, Nb, Ta, Mo; A = Al, Ga); powder data.

Compound	а	С	V	r(TM)	r(M')	Reference
Ti ₂ GaC	3.066	13.312	108.37	1.45	1.39	This work
Ti ₂ AlC	3.056	13.623	110.18	1.45	1.43	[42]
V ₂ GaC	2.938	12.84	95.98	1.36	1.39	[8]
V ₂ AlC	2.916	13.130	96.69	1.36	1.43	[12]
V ₂ Ga _{0.44} Al _{0.56} C	2.921	13.047	96.41	1.36	1.39/1.43	This work
V ₂ Ga _{0.57} Al _{0.43} C	2.928	12.998	96.51	1.36	1.39/1.43	This work
Cr ₂ GaC	2.893	12.665	91.65	1.28	1.39	This work
Cr ₂ AlC	2.860	12.82	90.81	1.28	1.43	[8]
Cr ₂ Ga _{0 4} Al _{0 6} C	2.875	12.679	90.77	1.47	1.39/1.43	This work
Nb ₂ GaC	3.131	13.565	115.16	1.47	1.39	[9d]
Nb ₂ AlC	3.103	13.83	115.32	1.47	1.43	[8]
Ta ₂ GaC	3.104	13.57	113.23	1.46	1.39	[9e]
Ta ₂ AlC	3.075	13.83	113.25	1.46	1.43	[8]
Mo ₂ GaC	3.017	13.18	103.90	1.40	1.39	[8]

MAX-phases have a strong tendency to form solid solutions which may be important for applications. Vegard's law is valid for all structural parameters. The example of the solid solution $V_2Ga_{1-x}Al_xC$ shows that the value of x can be triggered by the ratio Ga:Al of the melt.

Acknowledgments

Thanks are due to Bayerisches Geo-Institut (BGI, Universität Bayreuth) for the access to WDX measurements and to Detlev Krauße for his support. M.K. thanks the OBW (Ontario-Baden Württemberg) exchange program for support.

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